Sample Results Summary Sheet
Please return this form to the Curator for each allocated Sample

Sample ID: RB-QD04-0047-02-01
PI: Masayuki Uesugi

Type and date of analysis performed:
RB-QD04-0047-02-01 : TEM analysis (Dec. 25, 2013) by JEM-2800 at JEOL Ltd.

Elements or phases identified: (Mg, Si, olivine, pyroxene, aromatic carbon, etc.)
Carbon material (C, N, O) and Si

Contaminant phases identified: (Al, SUS, carbon particles, etc.)
N/A

Sample handling: (e.g. exposed in atmosphere, embedded in resin, polished, sliced by FIB or UMT)
Stored in N2 purged holder.
Exposed in atmosphere before and after introducing TEM sample chamber (a few minutes).

State of sample pre-analysis: (e.g. N2 hold, atmosphere, resin embedded, polished section, UTS) (please describe treatments and/or modifications for the sample you have done before your analysis)
RB-QD04-0047-02-01: Fixed on Cu grid, Stored in N2 purged holder.

State of sample post-analysis:
RB-QD04-0047-02-01: Fixed on Cu grid, Stored in N2 purged holder.

Analysis data Notes: (summary of the attached analysis data and/or images)

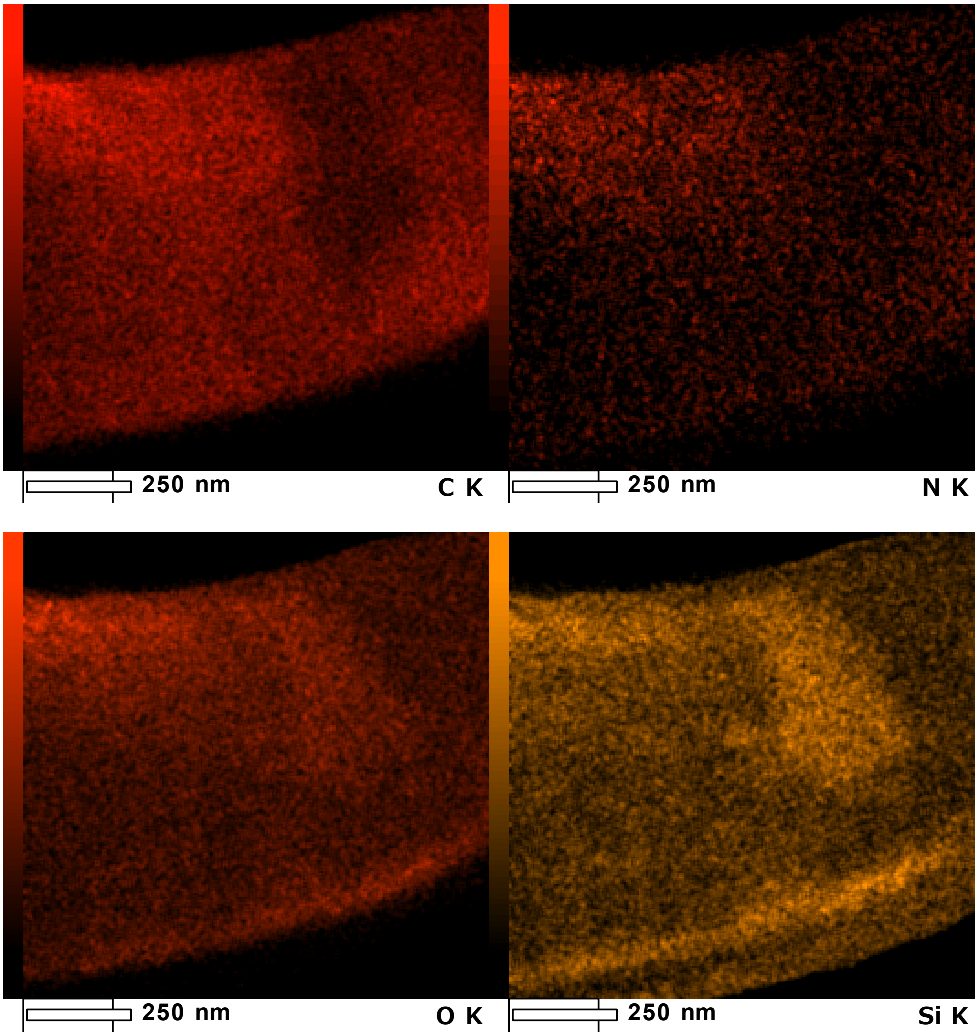

Fig. 1 RB-QD04-0047-02 : EDS mappings.